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APPLICATION NO.	FI	LING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.	
09/884,720	(06/19/2001	Richard R. Hengst	6096-01	2520	
26614	7590	02/24/2005		EXAMINER		
PEPE & H. 225 ASYLU	•	LLP	KACKAR, RAM N			
HARTFORI		103	ART UNIT	PAPER NUMBER		
	•			1763		

DATE MAILED: 02/24/2005

Please find below and/or attached an Office communication concerning this application or proceeding.

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		Application	on No.	Applicant(s)					
	Office Action Commons	09/884,72	20	HENGST, RICHARD	R				
	Office Action Summary	Examiner		Art Unit					
		Ram N Ka		1763					
The MAILING DATE of this communication appears on the cover sheet with the correspondence address Period for Reply									
THE - Exte after - If the - If NC - Failt Any	ORTENED STATUTORY PERIOD FOR MAILING DATE OF THIS COMMUNICA nsions of time may be available under the provisions of 37 SIX (6) MONTHS from the mailing date of this communic period for reply specified above is less than thirty (30) data period for reply is specified above, the maximum statuto ure to reply within the set or extended period for reply will, reply received by the Office later than three months after the patent term adjustment. See 37 CFR 1.704(b).	TION. 7 CFR 1.136(a). In no ever action. ays, a reply within the state ry period will apply and with by statute, cause the apple.	ent, however, may a reply be timutory minimum of thirty (30) days Ill expire SIX (6) MONTHS from lication to become ABANDONEI	nely filed s will be considered timely. the mailing date of this comm D (35 U.S.C. § 133).	nunication.				
Status									
1)🖂	Responsive to communication(s) filed o	on 02 December 2	004.	-					
·	This action is FINAL . 2b)⊠ This action is non-final.								
3)	^-			secution as to the m	erits is				
,—	closed in accordance with the practice under <i>Ex parte Quayle</i> , 1935 C.D. 11, 453 O.G. 213.								
Disposit	ion of Claims								
5)□ 6)⊠ 7)□	Claim(s) 1-4,6,9,11-27,29,30 and 32 is/are pending in the application. 4a) Of the above claim(s) 17-27 is/are withdrawn from consideration. Claim(s) is/are allowed. Claim(s) 1-4,6,9,11-16,29,30 and 32 is/are rejected. Claim(s) is/are objected to.								
	Claim(s) are subject to restriction	1 and/or election re	equirement.						
Applicat	ion Papers								
10)□	The specification is objected to by the Example The drawing(s) filed on is/are: a) Applicant may not request that any objection Replacement drawing sheet(s) including the The oath or declaration is objected to by	☐ accepted or b) n to the drawing(s) b e correction is require	ne held in abeyance. See ed if the drawing(s) is obj	e 37 CFR 1.85(a). lected to. See 37 CFR					
Priority (ınder 35 U.S.C. § 119								
 12) Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f). a) All b) Some * c) None of: 1. Certified copies of the priority documents have been received. 2. Certified copies of the priority documents have been received in Application No 3. Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)). * See the attached detailed Office action for a list of the certified copies not received. 									
2) Notic 3) Inform	t(s) e of References Cited (PTO-892) e of Draftsperson's Patent Drawing Review (PTO-0 mation Disclosure Statement(s) (PTO-1449 or PTC r No(s)/Mail Date		4) Interview Summary Paper No(s)/Mail Da 5) Notice of Informal Pa	ite	i2)				

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DETAILED ACTION

Continued Examination Under 37 CFR 1.114

1. A request for continued examination under 37 CFR 1.114, including the fee set forth in 37 CFR 1.17(e), was filed in this application after final rejection. Since this application is eligible for continued examination under 37 CFR 1.114, and the fee set forth in 37 CFR 1.17(e) has been timely paid, the finality of the previous Office action has been withdrawn pursuant to 37 CFR 1.114. Applicant's submission filed on 12/2/2004 has been entered.

Claim Rejections - 35 USC § 103

- 2. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
 - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 3. Claims 1-4, 6, 11-15, 29-30 and 32 are rejected under 35 U.S.C. 103(a) as being unpatentable over Richard R Hengst (US 5931666) in view of Lu at al (US 5904778) as evidenced by Breidenbach et al (US 5562774) and Hotate et al (US 5448418).

Hengst et al disclose a vertical wafer boat with plurality of support rods for supporting plurality of silicon wafers having ceramic body of siliconized SiC (Col 5 line 42-45), having ceramic coating of SiC to prevent migration of impurities (Col 5 line 32-45) and surface roughness to prevent slip of less than 1 µm (Col 4 lines 14-22), horizontal base, top plate, support rods, plurality of slots, each having ceramic coating and surface finish (Fig 1).

Hengst et al disclose ceramic coating of silicon carbide but do not disclose its thickness.

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Lu et al disclose that protective SiC coating of 100µm or less were well known (Col 6 line 21-23). Hotate et al, incorporated by Lu et al (Lu et al - Col 6 line 17) teaches that too thick coating of CVD–SiC on SiC base may develop defects due to occlusion of particles (Hotate et al-Col 1 lines 20-25). Hotate et al further teach that coatings 30-300 micron are preferable (Col 2 lines 8-13).

While Hotate et al teach the desirability of having the film thin in the context of the particular situation of SiC film over SiC, it is well known in general that thick films compared to thin films may have less adhesion. Breidenbach et al teach (Col 1 lines 12-16) that thicker films flake off easily. This observation is known and documented extensively in the art.

Therefore it would have been obvious for one having ordinary skill in the art at the time invention was made to have a thickness of less than 100 microns because too thick a layer may have problems due to a tendency to peel and acquire other defects and too thin layer may not provide adequate protection.

4. Claims 1-4, 6, 9, 11-15, 29-30 and 32 are rejected under 35 U.S.C. 103(a) as being unpatentable over Inaba et al (JP 11016993) which later became (US Patent 6093644) in view of Lu at al (US 5904778).

Inaba et al disclose a vertical wafer boat for supporting silicon wafers having ceramic body (Fig 1 and Col 1 line 34) having ceramic coating to prevent migration of impurities (Col 1 line 20) and surface finish over the coating to prevent slip in substrates of large diameters (Col 1 line 20) and at high temperature (Col 1 line 13), maximum roughness of the finish less than 10 µm and an impurity of less than 0.1 ppm (Col 3 line 14 and 15), horizontal base (Fig 1-13), top plate (Fig 1-12), support rods (Fig 1-11) and plurality of slots (Fig -14), each having ceramic

coating and surface finish (Col 2 line 47). Inaba et al disclose that the ceramic body could be Si-SiC (Col 4 lines 24-27)

Inaba et al disclose ceramic coating of silicon carbide but do not disclose its thickness.

Lu et al disclose SiC coating on sintered Silicon carbide being $100\mu m$ or less (Col 6 line 21-23).

Therefore it would have been obvious for one having ordinary skill in the art at the time invention was made to have a thickness of less than 100 microns because too thick a layer may have problems due to a tendency to peel and acquire other defects and too thin layer may not provide adequate protection.

5. Claim 16 is rejected under 35 U.S.C. 103(a) as being unpatentable over Inaba et al (JP 11016993) in view of Lu at al (US 5904778) as applied to claims 12 or Richard R Hengst (US 5931666) in view of Lu at al (US 5904778) as applied to claims 12 and further in view of Larry S Wingo (US 6171400).

Inaba et al or Richard R Hengst both, disclose a vertical wafer boat for supporting silicon wafers having ceramic body but do not disclose a stress relief slot and location notch.

Wingo discloses wafer boat having both stress relief slot and notches at the base (Fig 1).

Therefore it would have been obvious for one having ordinary skill in the art at the time invention was made to use the teaching of Wingo so as to be able to avoid problems due to thermal expansion and be able to place the boat correctly on processing platform.

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Response to Amendment

Applicant's arguments filed 12/02/2004 have been fully considered but they are not persuasive.

The applicant argues that one of ordinary skill in the art at the time of invention would not have looked at Lu et al to set the thickness of coating in Hengst since Lu et al is directed to a different discipline then that of Hengst.

Lu et al is directed to a semiconductor processing equipment and its teaching of protective layer of CVD- SiC is relevant to both etching as well as deposition since both may present corrosive and contaminating environment to components exposed to them and a protective coating may be advantageous in both cases.

The applicant argues that there is no support for the assertion that thicker layer may have a tendency to peel except in the applicants own disclosure.

This issue is addressed above in the rejection.

The applicant argues that Hengst fails to teach surface finish of less than 1.0 micron in the context of ceramic coating. The applicant further argues that Hengst discloses the surface finish less than 1.0 micron merely in passing.

Examiner disagrees.

Hengst has extensively studied the issue of slip as related to surface finish and teaches the reason of why low roughness is advantageous (Col 4 lines 14-22). To dismiss it as "in passing " seems inappropriate. To say that Hengst has not disclosed this in context of CVD SiC layer is also not correct since the relevant issue is only roughness and it is discussed in the context of CVD coating too (Col 5 lines 37-40).

Regarding the additional limitation of silicon impregnated silicon carbide, both Hengst (siliconized) and Inaba et al (Si-SiC) disclose a composite of silicon and Silicon Carbide. Since this is product by process claim its determination of patentability is based on the product itself and not on its method of production. If the product in the product-by-process claim is the same as or obvious from a product of the prior art, the claim is unpatentable even though the prior product was made by a different process." In re Thorpe, 777 F.2d 695, 698, 227 USPQ 964, 966 (Fed. Cir. 1985).

Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Ram N Kackar whose telephone number is 571 272 1436. The examiner can normally be reached on M-F 8:00 A.M to 5:P.M.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Gregory Mills can be reached on 571 272 1439. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

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